



P/1071-1593 CIP

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Gaku KAMITANI	Date	: July 28, 2004
Serial No.	: 10/601,718	Group Art Unit : 2863
Filed	: June 23, 2003	Examiner : Michael P. Nghiem
Confirmation No.	: 8700	
For	: METHOD FOR CORRECTING MEASUREMENT ERROR, METHOD OF DETERMINING QUALITY OF ELECTRONIC COMPONENT AND DEVICE FOR MEASURING CHARACTERISTIC OF ELECTRONIC COMPONENT	

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUBMISSION

Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience of the Examiner.

JP H08-15348 was cited and made of record in the parent case, U.S. Patent 6,697,749.

An English-language abstract is enclosed.

The other enclosure is the published manual described in the specification under "Description of the Related Art." A translation is enclosed.

The Examiner is requested to sign and return the enclosed form to the undersigned.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on July 28, 2004:

James A. Finder

Name of applicant, assignee or
Registered Representative

Signature

July 28, 2004

Date of Signature

Respectfully submitted,

James A. Finder

Registration No.: 30,173

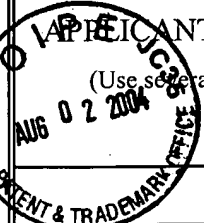
OSTROLENK, FABER, GERB & SOFFEN, LLP

1180 Avenue of the Americas

New York, New York 10036-8403

Telephone: (212) 382-0700

JAF:msd

		Application 10/601,718		OFGS File No. P/1071-1593 CIP			
		Applicant Gaku KAMITANI					
		Filing Date June 23, 2003		Group Art Unit 2863			
U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
	08-015348	01-1996	Japan			x	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
		HP 4284A Precision LCR Meter Instruction Manual, pp. 6-14 to 6-19 (December 1966)					
Examiner		Date Considered					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							